

# LATM2010 11th IEEE Latin-American TestWorkshop



Punta del Este, Uruguay March 28-31, 2010

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# **LATW**2010

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# **Call for Papers**

The IEEE Latin-American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin America and all over the world to present and discuss various aspects of system, board and component testing and fault-tolerance with design, manufacturing and field considerations in mind.

#### Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Board and System Test
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design Verification/Validation
- Design for Manufacturability
- Design of Reliable Embedded Software
- D&T for Electromagnetic Compatibility
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW - Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation Hardening Techniques
- System-on-Chip Test
- Yield Optimization

#### **Topic Coordinators:**

- Analog and Mixed-Signal M. Renovell LIRMM, France
- DFT & BIST A. Orailoglu, UC San Diego, USA
- Electromagnetic Compatibility E. Sicard, INSA Toulouse, France
- On-line Test and Fault Tolerance D. K. Pradhan, Univ. of Bristol, UK
- Radiation Ground Testing R. Ecoffet, CNES, France
- Software Testing S. Vergilio, UFPR, Brazil
- Verification and High Level Test M. P. Garcia, Univ. Carlos III, Spain

#### Paper Submission Information:

Those interested in presenting recent results at the workshop are invited to submit either an ex-tended abstract, one to three pages long, or a full length paper. PDF electronic submissions should be done via the workshop webpage: http://latw.tttc-events.org/. Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, of the contact person and the presenter. Detailed instructions are available at the workshop web page. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information please contact one of the Program Chairs.

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October 31st, 2009 **Submission deadline:** Notification of acceptance: December 9th, 2009 Camera Ready: January 9th, 2010

ATW2010 will be held in Punta del Este, Uruguay, considered as being one of the most beautiful and prestigious seaside resorts in South America. Punta del Este can be easily reached by bus shuttle (about one hour, buses every hour) from the Montevideo International Airport. Uruguay is a neuralgic point of the Southern Common Market (Mercosur), between its two largest Member States: Argentina (two-hour ferryboat trip to Buenos Aires) and Brazil (less than three hours flight to the cities of Porto Alegre, Sao Paulo or Rio de Janeiro). At less than two-hour drive from Montevideo can be found Colonia del Sacramento, founded by the Portuguese in 1680, declared Cultural Humanity Heritage by Unesco.

Sponsored by: IEEE Computer Society Test Technology Technical Council (TTTC)

Organized by: TIMA (Grenoble, France)

Faculty of Engineering - UDELAR (Montevideo)

#### General Chairs:

R. Velazco - TIMA, France raoul.velazco@imag.fr Y. Zorian - Virage Logic Corp., USA yervant.zorian@viragelogic.com

#### Program Chairs:

- F. Vargas PUCRS, Brazil
- E. Cota UFRGS, Brazil

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- **Publication Chair:**

M. Lubaszewski, UFRGS, Brazil

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For Program Committee Members, please see the conference webpage







